Form PTO 1449	U.S. DEPARTMENT OF COMMERCE			ATTY DOCKET NO.		SERIAL NO.		
(Modified)		PATENT AND TRA	DEMARK OFFICE	249971US6CONT		NEW APPLICATION		
			APPLICANT					
LIST OF	REFE	RENCES CITED BY AF	PPLICANT	Erich BAYER				
				FILING DATE		GROUP .		
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)								
	AX							
	AY							
	AZ	1 00				Additional References sheet(s) attached		
Examiner / L					Date Considered 3/13/07			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								